

Notice of References Cited	Application/Control No. 10/765,919	Applicant(s)/Patent Under Reexamination HATAKEYAMA ET AL.	
	Examiner Sin J. Lee	Art Unit 1752	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0168581 A1	11-2002	Takeda et al.	430/270.1
*	B	US-2004/0068124 A1	04-2004	Hasegawa et al.	549/397
*	C	US-2002/0132182 A1	09-2002	Nishi et al.	430/270.1
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
/	U	DERWENT English abstract for JP 2001-278918 (Hatakeyama et al).
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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